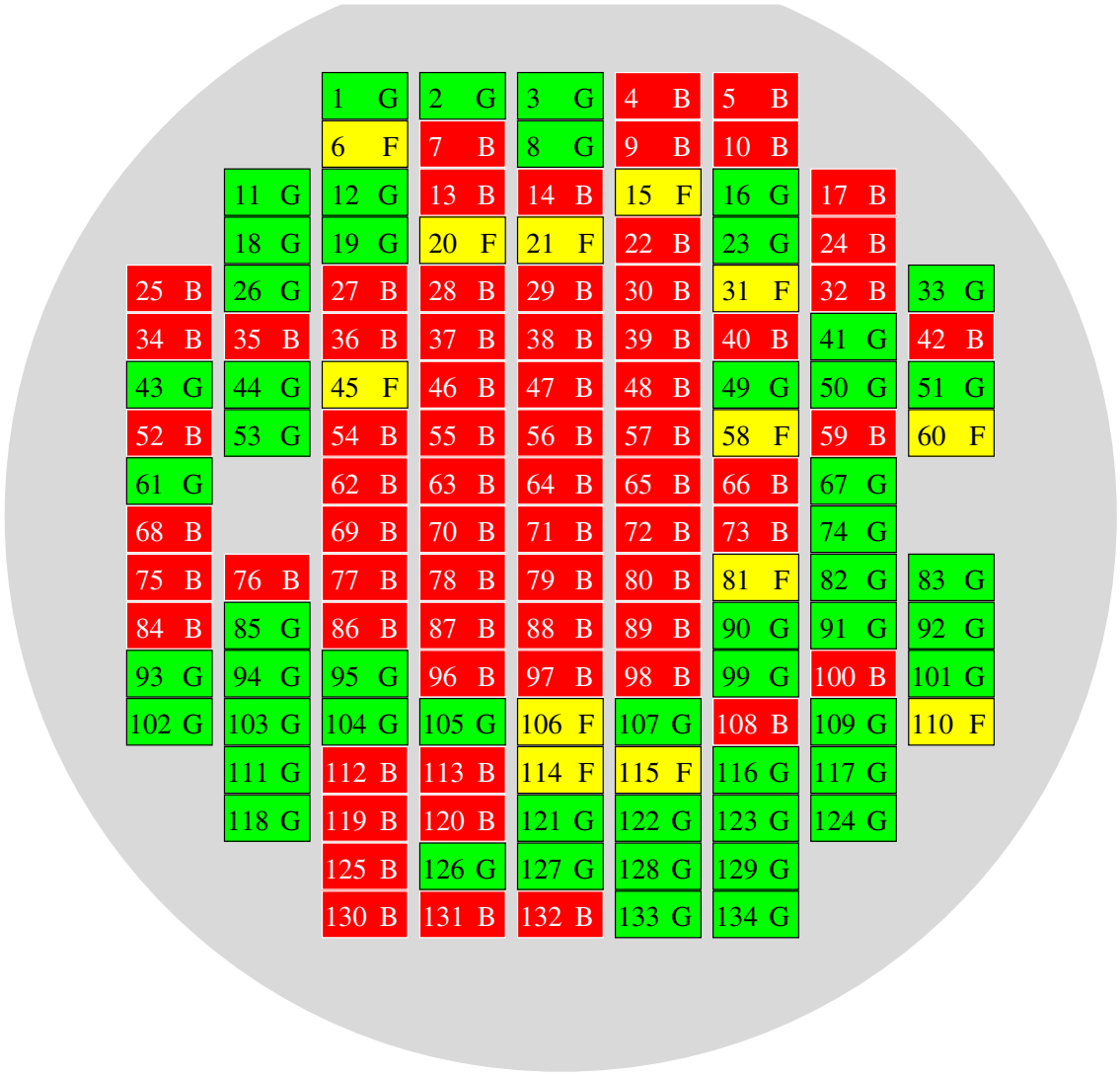
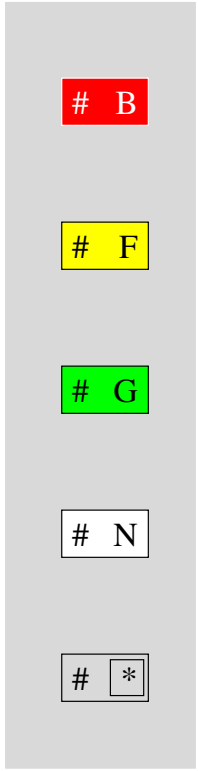
Die quality map for wafer 147 s/n: Y21316-12-14 (annealed, probe 2)

Date: 06/15/99





Bad die

Fair die

Good die

No info

Manually tagged